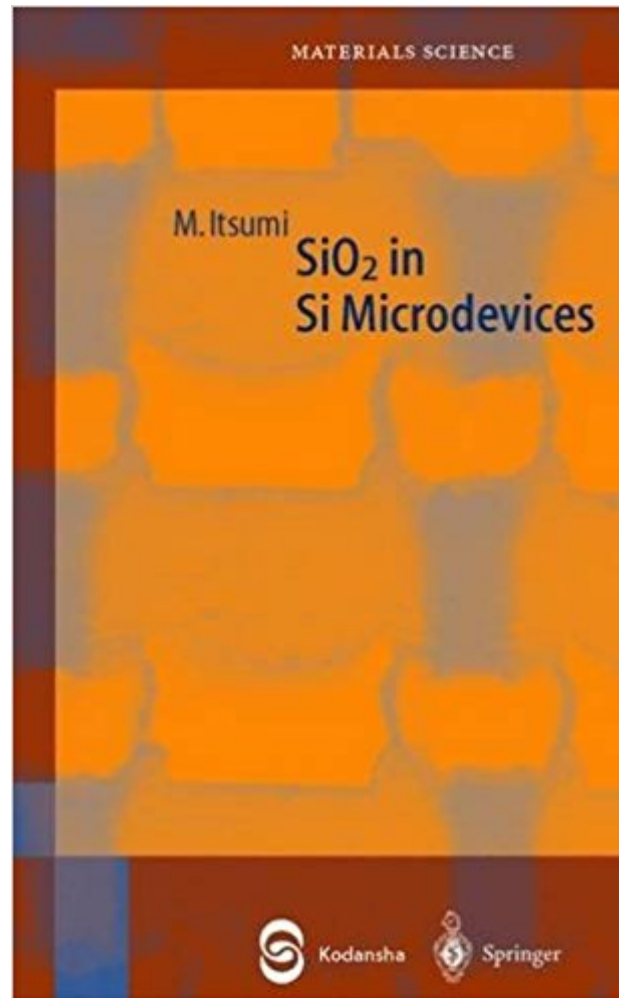




Ebook Directory
the best source of ebook

The book was found

SiO₂ In Si Microdevices



Synopsis

Electronic systems and digital computers are indispensable elements of modern multimedia technologies and the Internet society. But their explosive advance would not have been possible without the extraordinary progress in VLSI technology using high-quality SiO₂. This volume addresses the thin gate oxides involved in the individual processes in fabrication, e.g. the growth, cleaning and thermal oxidation of silicon, metal interconnect formation, and photolithography. It describes new methods for observing defects in SiO₂ as well as novel approaches to eliminating such defects. The book will be a valuable resource for all materials scientists and engineers seeking to further advance the quality of silicon microdevices.

Book Information

Series: Springer Series in Materials Science (Book 56)

Hardcover: 334 pages

Publisher: Springer; 2003 edition (January 17, 2003)

Language: English

ISBN-10: 3540433392

ISBN-13: 978-3540433392

Product Dimensions: 6.1 x 0.8 x 9.2 inches

Shipping Weight: 1.4 pounds (View shipping rates and policies)

Average Customer Review: Be the first to review this item

Best Sellers Rank: #2,468,508 in Books (See Top 100 in Books) #92 in [Books > Engineering & Transportation > Engineering > Electrical & Electronics > Circuits > VLSI & ULSI](#) #352 in [Books > Science & Math > Physics > Nanostructures](#) #394 in [Books > Science & Math > Technology > Nanotechnology](#)

Customer Reviews

Electronic systems and digital computers are an indispensable element of modern multimedia technologies and the Internet society. But their explosive advance would not have been possible without the extraordinary progress in VLSI technology using high-quality SiO₂. This volume addresses the thin gate oxides involved in the individual processes in fabrication, e.g. the growth, cleaning and thermal oxidation of silicon, metal interconnect formation, and photolithography. It describes new methods for observing defects in SiO₂ as well as novel approaches to eliminating such defects. The book will be a valuable resource for all materials scientists and engineers seeking to further advance the quality of silicon microdevices.

[Download to continue reading...](#)

SiO₂ in Si Microdevices

[Contact Us](#)

[DMCA](#)

[Privacy](#)

[FAQ & Help](#)